

### 12500 TI Boulevard, MS 8640, Dallas, Texas 75243

# PCN#20141208000 Assembly site move from Amkor K1 to Amkor P1 for Select Devices Change Notification / Sample Request

**Date:** 12/16/2014

To: Newark/Farnell PCN

#### Dear Customer:

Amkor K1 (Korea) is closing its facility by 2015. This product change announcement is to support transfer of products in the QFN package to alternate sites. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days to ensure you can complete your evaluation and product transfer to the new site can be completed prior to the Amkor K1 site closure.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN www admin team@list.ti.com).

Sincerely,

PCN Team SC Business Services Phone: +1(214) 480-6037 Fax: +1(214) 480-6659

## 20141208000 Attachment: 1

## **Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	<b>CUSTOMER PART NUMBER</b>
CC2560ARVMR	null
CC2560ARVMT	null
CC2564BRVMT	null
MSP430F133IRTDT	null
MSP430F149IRTDR	null
MSP430F1611IRTDT	null
MSP430F413IRTDT	null
CC2564RVMR	null
CC2564RVMT	null
MSP430F135IRTDT	null
MSP430F1471IRTDT	null
MSP430F147IRTDT	null
MSP430F1481IRTDT	null
MSP430F148IRTDT	null
MSP430F1491IRTDT	null
MSP430F149IRTDT	null
MSP430F156IRTDT	null
MSP430F157IRTDT	null
MSP430F1610IRTDT	null
MSP430F167IRTDT	null
MSP430F168IRTDT	null

Technical details of this Product Change follow on the next page(s).

PCN Nu	<b>PCN Number:</b> 20141208000 <b>PCN Date:</b> 12/16/2014							12/16/2014			
Title:	Title: Assembly site move from Amkor K1 to Amkor P1 for Select Devices										
Custom	er Contact:	PCN A	Manager		Phone	+1(214)4	80-6037	7	Dept:	Qua	ality Services
Propose	ed 1 <sup>st</sup> Ship Da	ite:	03/16	5/20	115	Estimated S Availability	-			•	vided at equest
Change	Type:										
Asse	embly Site				Desig				Wafer	Bum	p Site
	embly Process				Data 9						p Material
	embly Material			Ц		umber chang	le	<u> </u>			p Process
	hanical Specif			Ц	Test S			<u>Ц</u>	Wafer		
⊠ Pacl	king/Shipping/	Label	ing		Test P	rocess		<u> </u>			<u>Materials</u>
									Wafer	Fab	Process
	tion of Chang				PCN	l Details					
Mount ( Mold Co	Assembly site move from Amkor K1 to Amkor P1 for Select Devices. Material differences are as follows:     Group 1 Device Amkor K1 Amkor P1   Mount Compound 101361223 4208458   Mold Compound 101319571 4211649   Wire type Au Au, Cu   Lead Finish Matte Sn NiPdAu     Group 2 Device										
	Amkor K		<b>&lt;1</b>	Amk	or P1						
Mount (	Compound	1013612		23	420	4208458					
Mold Co	mpound	1013195		71	421	4211649					
Reason for Change:											
Closure of the Amkor K1 assembly facility. Continuity of supply.											
Anticipa	ited impact o	n Foi	rm, Fit	, Fı	ınctior	n, Quality or	Reliab	ilit	y (posit	ive	/ negative):
None											

**Changes to product identification resulting from this PCN:** 

# Sample Product Shipping Label (not actual product label)

**Group 1:** Assembly Site

Amkor K1	Assembly Site Origin (22L)	ASO: AMN
Amkor P1	Assembly Site Origin (22L)	ASO: AKR

INSTRUMENTS MADE IN: Malaysia

MSL 2 /260C/1 YEAR SEAL DT 03/29/04 MSL 1 /235C/UNLIM

OPT: ITEM:

(L)T0:1750

(1P) SN74LS07NSR (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483SI2

(2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA

0033317 (22L) ASO: MLA (23L) ACO: MYS

ASSEMBLY SITE CODES: AMN =7, AKR = 4

# **Product Affected Group: Group 1**

MSP430F133IRTDR	MSP430F1491IRTDR	MSP430F1610IRTDT	MSP430F412IRTDT
MSP430F133IRTDT	MSP430F1491IRTDT	MSP430F1611IRTDR	MSP430F413IRTDR
MSP430F135IRTDR	MSP430F149IRTDR	MSP430F1611IRTDT	MSP430F413IRTDT
MSP430F135IRTDT	MSP430F149IRTDRG4	MSP430F1612IRTDR	MSP430F415IRTDR
MSP430F1471IRTDR	MSP430F149IRTDT	MSP430F1612IRTDT	MSP430F415IRTDT
MSP430F1471IRTDT	MSP430F155IRTDR	MSP430F167IRTDR	MSP430F417IRTDR
MSP430F147IRTDR	MSP430F155IRTDT	MSP430F167IRTDT	MSP430F417IRTDT
MSP430F147IRTDT	MSP430F156IRTDR	MSP430F168IRTDR	MSP430V119IRTDR
MSP430F1481IRTDR	MSP430F156IRTDT	MSP430F168IRTDT	MSP430V170IRTDR
MSP430F1481IRTDT	MSP430F157IRTDR	MSP430F169IRTDR	
MSP430F148IRTDR	MSP430F157IRTDT	MSP430F169IRTDT	
MSP430F148IRTDT	MSP430F1610IRTDR	MSP430F412IRTDR	

# **Product Affected Group: Group 2**

CC2560ARVMR	CC2564NSRVMR	CC2567RVMR
CC2560ARVMT	CC2564NSRVMT	CC2567RVMT
CC2564BRVMR	CC2564RVMR	CC2569RVMR
CC2564BRVMT	CC2564RVMT	CC2569RVMT

# Group 1 Qualification Report MSP430F1611 AMKOR K1 to P1 Assembly Transfer and Cu Wire Conversion

### **Product Attributes**

Attributes	MSP430F1611IRTD Cu Wire	MSP430F1611IRTD Au Wire
Assembly Site	AMKOR P1	AMKOR P1
Package Family	QFN, 9.0 X 9.0 MM, 0.5MM Lead Pitch	QFN, 9.0 X 9.0 MM, 0.5MM Lead Pitch
Flammability Rating UL 94-V0		UL 94-V0
Wafer Fab Site	TSMC FAB 3	TSMC FAB 3
Wafer Fab Process	TSMC035UM	TSMC035UM

<sup>-</sup> Qual Device MSP430F1611IRTD qualified at LEVEL3-260C

### **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	MSP430F1611IRTD Cu Wire	MSP430F1611IRTD Au Wire
HAST	HAST 110C/85% RH	264 Hours	3/231/0	3/231/0
AC	Autoclave 121C	96 Hours	3/231/0	3/231/0
TC	Temp Cycle -65/150C	500 Cycles	3/231/0	3/231/0
HTSL	Bake 170C	420 Hours	3/231/0	3/231/0
SATM	Salt Atmosphere Testing	24 Hours	-	3/66/0
WBS	Wire Bond Shear	Per Assy Site Specifications	3/90/Pass	3/90/Pass
WBP	Wire Bond Pull	Per Assy Site Specifications	3/90/Pass	3/90/Pass
SD	Pb Free Surface Mount Solderability	Per Assy Site Specifications	-	1/22/Pass
PD	Physical Dimensions	Per Assy Site Specifications	-	1/5/Pass
XRAY	X-RAY	Per Assy Site Specifications	1/5/Pass	-

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/340 Hours
- 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
   The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and
- 170C/420 Hours
   The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

**Green/Pb-free Status:** 

Qualified Pb-Free(SMT) and Green

# Group 2 Qualification Report Qualification of Orca Offload from Amkor K1 to Amkor P1

# **Product Attributes**

	Qual Device: BL6450QRVMR	QBS Device: BL6450QRVMR	QBS Device: BL6450QRVMR
Die Attributes			
Wafer Fab Site	TSMC F-14	TSMC F-14	TSMC F-14
Wafer Fab Process	1218C021.M6RF	1218C021.M6RF	1218C021.M6RF

Package Attributes			
Assembly Site	Amkor P1	Amkor K1	Amkor K1
Package Family	PVQFN	PVQFN	WSP
Package Designator	RVM	RVM	YFV
Package Size (mils)	314.96 X 314.96	314.96 X 314.96	116.42 x 129.68
Body Thickness (mils)	0.85	0.85	19.68
Pin Count	76	76	54
Bump Composition	-	-	Sn/Ag/Cu (LF35)
Lead Frame Material	Cu	Cu	-
Lead Finish	NiPdAu	NiPdAu	-
Lead Pitch (mils)	0.6	0.6	-
Mount Compound	101340002	101340002	-
Mold Compound	101317124	101317124	-
Bond Wire Composition	Au	Au	-
Bond Wire Diameter (mils)	0.7	0.7	-
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0

<sup>-</sup> Qual Devices qualified at LEVEL3-260C

# **Qualification Plan**

			RuaiiiiCatiOi	i i iaii		
Туре	#	Test Name / Condition	Duration	Qual Device: BL6450QRVMR Expected Date	QBS Device: BL6450QRVMR	QBS Device: BL6450QRVMR
Test G	rou	p A - Accelerated Environment Stress	Test			
PC	A1	PreCon Level 3	3 Cyc/260C +5 / -0C	2/28/2015	-	-
THB	A2	THB 85/85 (Automotive)	1000 Hr	2/28/2015	-	-
UHAST	А3	Unbiased HAST 130C/85%RH	96 Hr	2/28/2015	-	-
TC	A4	Temperature Cycle, -50/150C	500 Cyc	2/28/2015	-	-
HTSL	A6	High Temp Storage Bake 150C	1000 Hr	2/28/2015	-	-
Test G	irou	p B - Accelerated Lifetime Simulation	Test			
HTOL	B1	HTOL, 125C	1000 Hr	-	3/230/0	-
ELFR	B2	Early Life Failure Rate, 125C	8 Hr	-	3/1197/0	-
ELFR	B2	Early Life Failure Rate, 125C	48 Hr	-	3/1197/0	-
Test G	irou	p C - Package Assembly Integrity Tes	ts			
WBS	C1	Wire Bond Shear (Ppk > 1.67 and Cpk > 1.33)	30 bonds/5 devices	2/28/2015	-	-
WBP	C2	Wire Bond Pull (Ppk > 1.67 and Cpk > 1.33)	30 bonds/5 devices	2/28/2015	-	-
SD	C3	Solderability >95% Lead Coverage	8 Hr/steam age	2/28/2015	-	-
PD	C4	Physical Dimensions (Cpk>1.33 Ppk>1.67)		2/28/2015	-	-
SBS	C5	Solder Ball Shear (Ppk > 1.67 and Cpk > 1.33)	Post HTSL/Bump	N/A	-	-
SBS	C5	Solder Ball Shear (Ppk > 1.67 and Cpk > 1.33)	Time Zero/Bump	N/A	-	-
SBS	C5	Solder Ball Shear (Ppk > 1.67 and Cpk > 1.33)	Post 500 Temp Cyc/Bump	N/A	-	-
LI	C6	Lead Integrity		N/A	-	-
Test G	Test Group E - Electrical Verification					
HBM	E2	ESD - HBM - Q100 all pins	500V	-	1/3/0	-
CDM	ЕЗ	ESD - CDM - Q100	250V, 750V (corner pins)	-	1/3/0	-
LU	E4	Latch- Up	Ta(max)	-		3/18/0
ED	E5	Electrical Distributions		-	3/30/Pass	-
CHAR	E7	Characterization		-	1/30/Pass	-

- Preconditioning will be performed for Unbiased HAST, unbiased/Biased HAST, Temperature Cycle, and HTSL, as applicable
- The following are equivalent HTSL options based on an activation energy of  $0.7 \mathrm{eV}: 150 \mathrm{C}/1 \mathrm{k}$  Hours, and  $170 \mathrm{C}/420$  Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

#### **Green/Pb-free Status:**

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com